Ultramicroscopy 21 (1987) 403–404
North-Holland, Amsterdam

AUTHOR INDEX TO VOLUME 21

Admon, U., Specimen shift correction in tilting experiments 21 (1987) 297

Bender, H., see De Jong 21 (1987) 373
Berendsen, W. and J. Pieters, Editors, Abstracts of papers presented at The Netherlands Society of Electron Microscopy Annual Meeting, Wageningen, 1986 21 (1987) 181
Berger, S.D., D. Imeson and R.H. Milne, Experimental determination of the probe profile in a dedicated scanning transmission electron microscope 21 (1987) 293
Berriman, J., see Trinick 21 (1987) 393
Bostanjoglo, O., R.P. Tornow and W. Tornow, Nanosecond-exposure electron microscopy of laser-induced phase transformations 21 (1987) 367
Bradley, C.R., see Gibbons 21 (1987) 305
Britton, E.G. and W.M. Stobbs, The analysis and application of dynamical effects in HOLZ patterns 21 (1987) 1
Bullough, P. and R. Henderson, Use of spot-scan procedure for recording low-dose micrographs of beam-sensitive specimens 21 (1987) 223
Buseck, P.R., see Rask 21 (1987) 321

Carpenter, R.W., see Kim 21 (1987) 327
Cheng, S.C., see Egerton 21 (1987) 231
Cheng, S.C., Localization distance of plasmons excited by high-energy electrons 21 (1987) 291
Christenson, K.K. and J.A. Eades, The sharpness of Kikuchi lines and their use in setting the height of the objective aperture in a TEM 21 (1987) 101
Coene, W., see De Jong 21 (1987) 373
Colliex, C., see Mory 21 (1987) 171
Cowley, J.M., see Wang 21 (1987) 77
Cowley, J.M., see Fan 21 (1987) 125
Cowley, J.M., see Mory 21 (1987) 171
Cowley, J.M., see Wang 21 (1987) 335
Cowley, J.M., see Wang 21 (1987) 347
Cox, G., see Venables 21 (1987) 33

De Jong, A.F., H. Bender and W. Coene, Actual comparison of experimental and simulated lattice images of the GaAs/AlAs interface 21 (1987) 373
Dorset, D.L. and F. Zemlin, Specimen movement in electron-irradiated paraffin crystals – a model for initial beam damage 21 (1987) 263

Eades, J.A., see Christenson 21 (1987) 101
Echeverría, O., see Esquivel 21 (1987) 103
Egerton, R.F. and S.C. Cheng, Measurement of local thickness by electron energy-loss spectroscopy 21 (1987) 231
Esquivel, C., P. Rovira, O. Echeverría and G.H. Vázquez-Nin, A simple staining method for chromatin in electron microscopy compatible with serial sectioning 21 (1987) 103

Fan, G.Y. and J.M. Cowley, The simulation of high resolution images of amorphous thin films 21 (1987) 125
Fraundorf, P.B., see Gibbons 21 (1987) 305
Furuno, S., see Izui 21 (1987) 399

Gat, R. and F.W. Schapink, Convergent-beam electron diffraction from GaAs/AlAs superlattices 21 (1987) 389
Gibbons, P.C., C.R. Bradley and P.B. Fraundorf, How to remove multiple scattering from core-excitation spectra. III. Varying the mean free path 21 (1987) 305
Giorgio, S. and R. Kern, Defects in a lamellar polymer by high-resolution electron microscopy 21 (1987) 157
Giorgio, S. and R. Kern, Associations between polymer membranes and globular molecules 21 (1987) 251
Golob, P., see Hofer 21 (1987) 379

Hainfeld, J.F., see Monson 21 (1987) 147
Hawkes, P.W., Issues, proceedings and other business 21 (1987) 299
Henderson, R., see Bullough 21 (1987) 223
Hofer, F., EELS quantification of M edges by using oxidic standards 21 (1987) 63
Hofer, F. and P. Golob, New examples for near-edge fine structures in electron energy loss spectroscopy 21 (1987) 379
Horita, Z., T. Sano and M. Nemoto, Simplication of X-ray absorption correction in thin-sample quantitative microanalysis 21 (1987) 271

Izui, K. and S. Furuno, Comment to the images of silicon in ⟨110⟩ orientation 21 (1987) 399
Imeson, D., see Berger 21 (1987) 293

Jésior, J.-C. and R.H. Wade, Electron-irradi-

ation-induced flattening of negatively stained 2D protein crystals 21 (1987) 313

Kern, R., see Giorgio 21 (1987) 157
Kern, R., see Giorgio 21 (1987) 251
Kilaas, R., M.A. O'Keefe and K.M. Krishnan, On the inclusion of upper Laue layers in computational methods in high resolution transmission electron microscopy 21 (1987) 47
Kim, M.J. and R.W. Carpenter, TEM specimen heating during ion beam thinning: microstructural instability 21 (1987) 327
Koster, A.J., A. van den Bos and K.D. van der Mast, An autofocus method for a TEM 21 (1987) 209
Krishnan, K.M., see Kilaas 21 (1987) 47

Lynch, D. and C. Rossouw, Non-zeroth-order Laue zone effects and ALCHEMI 21 (1987) 69

Mansfield, J.F., P.R. Okamoto. L.E. Rehn and N.J. Zaluzec, Radiation effects on X-ray microanalysis of a light element alloy in a medium-voltage electron microscope 21 (1987) 13
Maslen, V.W., see Rossouw 21 (1987) 277
Milne, R.H., see Berger 21 (1987) 293
Miner, B.A., see Rask 21 (1987) 321
Monson, K.L., J.S. Wall and J.F. Hainfeld, Visibility and stability of a 12-tungsten atom complex in the scanning transmission electron microscope 21 (1987) 147
Mory, C., C. Colliex and J.M. Cowley, Optimum defocus for STEM imaging and microanalysis 21 (1987) 171

Nemoto, M., see Horita 21 (1987) 271

Okamoto, P.R., see Mansfield 21 (1987) 13
O'Keefe, M.A., see Kilaas 21 (1987) 47

Pieters, J., see Berendsen 21 (1987) 181

Rask, J.H., B.A. Miner and P.R. Buseck, Determination of manganese oxidation states in solids by electron energy-loss spectroscopy 21 (1987) 321
Rehn, L.E., see Mansfield 21 (1987) 13
Reimer, L. and M. Ross-Messemer, Top–bottom effect in energy-selecting transmission electron microscopy 21 (1987) 385
Ross-Messemer, M., see Reimer 21 (1987) 385
Rossouw, C., see Lynch 21 (1987) 69
Rossouw, C.J. and V.W. Maslen, Localization and ALCHEMI for zone axis orientations 21 (1987) 277
Rovira, P., see Esquivel 21 (1987) 103

Sano, T., see Horita 21 (1987) 271
Schapink, F.W., see Gat 21 (1987) 389
Sekii, H., see Tanaka 21 (1987) 245
Shuman, H. and A.P. Somlyo, Electron energy loss analysis of near-trace-element concentrations of calcium 21 (1987) 23
Somlyo, A.P., see Shuman 21 (1987) 23
Stadelmann, P.A., EMS – a software package for electron diffraction analysis and HREM image simulation in materials science 21 (1987) 131
Stobbs, W.M., see Britton 21 (1987) 1

Tanaka, M., M. Terauchi and H. Sekii, Observation of dynamic extinction due to a glide plane perpendicular to an incident beam by convergent-beam electron diffraction 21 (1987) 245
Terauchi, M., see Tanaka 21 (1987) 245
Tornow, R.P., see Bostanjoglo 21 (1987) 367
Tornow, W., see Bostanjoglo 21 (1987) 367
Trinick, J. and J. Berriman, Zero-loss electron microscopy with the Zeiss EM902 21 (1987) 393

Van den Bos, A., see Koster 21 (1987) 209
Van der Mast, K.D., see Koster 21 (1987) 209
Van Heel, M., Similarity measures between images 21 (1987) 95
Van Heel, M., Angular reconstitution: a posteriori assignment of projection directions for 3D reconstruction 21 (1987) 111
Vázquez-Nin, G.H., see Esquivel 21 (1987) 103
Venables, J.A. and G. Cox, Computer modelling of field emission gun scanning electron microscope columns 21 (1987) 33

Wade, R.H., see Jésior 21 (1987) 313
Wall, J.S., see Monson 21 (1987) 147
Wang, Z.L. and J.M. Cowley, Surface plasmon excitation for supported metal particles 21 (1987) 77
Wang, Z.L. and J.M. Cowley, Excitation of the supported metal particle surface plasmon with external electron beam 21 (1987) 335
Wang, Z.L. and J.M. Cowley, Generation of surface plasmon excitation of supported metal particles by an external electron beam 21 (1987) 347

Zaluzec, N.J., see Mansfield 21 (1987) 13
Zemlin, F., see Dorset 21 (1987) 263

Ultramicroscopy 21 (1987) 405–407
North-Holland, Amsterdam

SUBJECT INDEX TO VOLUME 21

Analytical microscopy
Non-zeroth-order Laue zone effects and ALCHEMI, *Lynch and Rossouw* 21 (1987) 69
Measurement of local thickness by electron energy-loss spectroscopy, *Egerton and Cheng* 21 (1987) 231
Simplification of X-ray absorption correction in thin-sample quantitative microanalysis, *Horita, Sano and Nemoto* 21 (1987) 271
Localization and ALCHEMI for zone axis orientations, *Rossouw and Maslen* 21 (1987) 277
Localization distance of plasmons excited by high-energy electrons, *Cheng* 21 (1987) 291
Determination of manganese oxidation states in solids by electron energy-loss spectroscopy, *Rask, Miner and Buseck* 21 (1987) 321
Nanosecond-exposure electron microscopy of laser-induced phase transformations, *Bostanjoglo, Tornow and Tornow* 21 (1987) 367
New examples for near-edge fine structures in electron energy loss spectroscopy, *Hofer and Golob* 21 (1987) 379

Conventional electron microscopy
Defects in a lamellar polymer by high resolution electron microscopy, *Giorgio and Kern* 21 (1987) 157
Associations between polymer membranes and globular molecules, *Giorgio and Kern* 21 (1987) 251

Diffraction and optical diffraction
The analysis and application of dynamical effects in HOLZ patterns, *Britton and Stobbs* 21 (1987) 1
Non-zeroth-order Laue zone effects and ALCHEMI, *Lynch and Rossouw* 21 (1987) 69
Observation of dynamic extinction due to a glide plane perpendicular to an incident beam by convergent-beam electron diffraction, *Tanaka, Terauchi and Sekii* 21 (1987) 245
Convergent-beam electron diffraction from GaAs/AlAs superlattices, *Gat and Schapink* 21 (1987) 389

Electron energy loss spectroscopy
Electron energy loss analysis of near-trace-element concentrations of calcium, *Shuman and Somlyo* 21 (1987) 23
EELS quantification of M edges by using oxidic standards, *Hofer* 21 (1987) 63
Surface plasmon excitation for supported metal particles, *Wang and Cowley* 21 (1987) 77
Measurement of local thickness by electron energy-loss spectroscopy, *Egerton and Cheng* 21 (1987) 231
Localization distance of plasmons excited by high-energy electrons, *Cheng* 21 (1987) 291
How to remove multiple scattering from core-excitation spectra. III. Varying the mean free path, *Gibbons, Bradley and Fraundorf* 21 (1987) 305
Determination of manganese oxidation states in solids by electron energy-loss spectroscopy, *Rask, Miner and Buseck* 21 (1987) 321
Excitation of the supported metal particle surface plasmon with external electron beam, *Wang and Cowley* 21 (1987) 335
Generation of surface plasmon excitation of supported metal particles by an external electron beam, *Wang and Cowley* 21 (1987) 347
New examples for near-edge fine structure in electron energy loss spectroscopy, *Hofer and Golob* 21 (1987) 379
Top–bottom effect in energy-selecting transmission electron microscopy, *Reimer and Ross-Messemer* 21 (1987) 385
Zero-loss electron microscopy with the Zeiss EM902, *Trinick and Berriman* 21 (1987) 393

Electron probe microanalysis
Radiation effects on X-ray microanalysis of a light element alloy in a medium-voltage electron microscope, *Mansfield, Okamoto, Rehn and Zaluzec* 21 (1987) 13
Optimum defocus for STEM imaging and microanalysis, *Mory, Colliex and Cowley* 21 (1987) 171
Simplification of X-ray absorption correction in thin-sample quantitative microanalysis, *Horita, Sano and Nemoto* 21 (1987) 271

High resolution
Defects in a lamellar polymer by high-resolution electron microscopy, *Giorgio and Kern* 21 (1987) 157
Comment to the images of silicon in ⟨110⟩ orientation, *Izui and Furuno* 21 (1987) 399

Image processing, 3D reconstruction
On the inclusion of upper Laue layers in computational methods in high resolution

transmission electron microscopy, *Kilaas, O'Keefe and Krishnan* 21 (1987) 47
Similarity measures between images, *Van Heel* 21 (1987) 95
Angular reconstitution: a posteriori assignment of projection directions for 3D reconstruction, *Van Heel* 21 (1987) 111
The simulation of high resolution images of amorphous thin films, *Fan and Cowley* 21 (1987) 125
EMS – a software package for electron diffraction analysis and HREM image simulation in materials science, *Stadelmann* 21 (1987) 131
Actual comparison of experimental and simulated lattice images of the GaAs/AlAs interface, *De Jong, Bender and Coene* 21 (1987) 373

Instrumentation
Computer modelling of field emission gun scanning electron microscope columns, *Venables and Cox* 21 (1987) 33
An autofocus method for a TEM, *Koster, Van den Bos and Van der Mast* 21 (1987) 209
Top–bottom effect in energy-selecting transmission electron microscopy, *Reimer and Ross-Messemer* 21 (1987) 385
Zero-loss electron microscopy with the Zeiss EM902, *Trinick and Berriman* 21 (1987) 393

Methods and techniques
The sharpness of Kikuchi lines and their use in setting the height of the objective aperture in a TEM, *Christenson and Eades* 21 (1987) 101
An autofocus method for a TEM, *Koster, Van den Bos and Van der Mast* 21 (1987) 209
Use of a spot-scan procedure for recording low-dose micrographs of beam-sensitive specimens, *Bullough and Henderson* 21 (1987) 223
Measurement of local thickness by electron energy-loss spectroscopy, *Egerton and Cheng* 21 (1987) 231
Specimen shift correction in tilting experiments, *Admon* 21 (1987) 297
How to remove multiple scattering from core-excitation spectra. III. Varying the mean free path, *Gibbons, Bradley and Fraundorf* 21 (1987) 305
Nanosecond-exposure electron microscopy of laser-induced phase transformations, *Bostanjoglo, Tornow and Tornow* 21 (1987) 367

New developments
EMS – a software package for electron diffraction analysis and HREM image simulation in materials science, *Stadelmann* 21 (1987) 131
Top–bottom effect in energy-selecting transmission electron microscopy, *Reimer and Ross-Messemer* 21 (1987) 385
Zero-loss electron microscopy with the Zeiss EM902, *Trinick and Berriman* 21 (1987) 393

Particle optics, theory
Computer modelling of field emission gun scanning electron microscope columns, *Venables and Cox* 21 (1987) 33

Radiation damage and contamination
Use of spot-scan procedure for recording low-dose micrographs of beam-sensitive specimens, *Bullough and Henderson* 21 (1987) 223
Specimen movement in electron-irradiated paraffin crystals – a model for initial beam damage, *Dorset and Zemlin* 21 (1987) 263
Electron-irradiation-induced flattening of negatively stained 2D protein crystals, *Jésior and Wade* 21 (1987) 313

Scanning transmission electron microscopy
Visibility and stability of a 12-tungsten atom complex in the scanning transmission electron microscope, *Monson, Wall and Hainfeld* 21 (1987) 147
Optimum defocus for STEM imaging and microanalysis, *Mory, Colliex and Cowley* 21 (1987) 171
Experimental determination of the probe profile in a dedicated scanning transmission electron microscope, *Berger, Imeson and Milne* 21 (1987) 293

Specimen preparation
A simple staining method for chromatin in electron microscopy compatible with serial sectioning, *Esquivel, Rovira, Echeverría and Vásquez-Nin* 21 (1987) 103
Electron-irradiation-induced flattening of negatively stained 2D protein crystals, *Jésior and Wade* 21 (1987) 313
TEM specimen heating during ion beam thinning: microstructural instability, *Kim and Carpenter* 21 (1987) 327

Surfaces, clusters, interfaces and particles
Surface plasmon excitation for supported metal particles, *Wang and Cowley* 21 (1987) 77
Observation of dynamic extinction due to a glide plane perpendicular to an incident beam by convergent-beam electron diffraction, *Tanaka, Terauchi and Sekii* 21 (1987) 245
Excitation of the supported metal particle surface plasmon with external electron beam, *Wang and Cowley* 21 (1987) 335
Generation of surface plasmon excitation of supported metal particles by an external electron beam, *Wang and Cowley* 21 (1987) 347
Actual comparison of experimental and simulated lattice images of the GaAs/AlAs interface, *De Jong, Bender and Coene* 21 (1987) 373

Abstracts / Announcements / Book reviews / Comments / Editorials / Reports / Miscellaneous

Special announcement, Study Course in Sicily 21 (1987) 179

Abstracts of papers presented at The Netherlands Society of Electron Microscopy Annual Meeting, Wageningen, December 1986, *Eds. Berendsen and Pieters* 21 (1987) 181

Issues, proceedings and other business, *Hawkes* 21 (1987) 299